Search Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/537,677	SCHULTE ET AL.	
Examiner	Art Unit	
Rip A. Lee	1713	

	SEAR	CHED	
Class	Subclass	Date	Examiner
536	53	05-51-5024	1
526	46		
526	170		
2576	943	4	
	1,11		
·			
	,		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR	
EAST	02-21-23	m_	
STN STructure search	02-21-200	AN_	
	·		
	<u> </u>		